

General Description

The MY10N80F is silicon N-channel Enhanced VDMOSFETS, obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy.

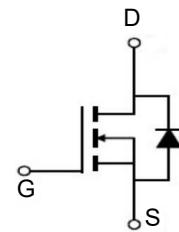
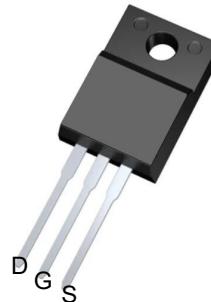


Features

V _{DSS}	800	V
I _D	10	A
P _D (T _C = 25 °C)	37	W
R _{DS(ON)} (at V _{GS} = 10V)	0.68	Ω

Application

- High efficiency switch mode power supplies
- Power factor correction
- Electronic lamp ballast



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
MY10N80F	TO-220F	MY10N80F	1000

Absolute Maximum Ratings (T_c=25 °C unless otherwise noted)

Symbol	Parameters	Ratings	Unit
V _{DSS}	Drain-Source Voltage	800	V
V _{GS}	Gate-Source Voltage-Continuous	±30	V
I _D	Drain Current-Continuous (Note 2)	10	A
I _{DM}	Drain Current-Single Plused (Note 1)	40	A
P _D	Power Dissipation (Note 2)	37	W
T _j	Max.Operating junction temperature	150	°C/W

Electrical Characteristics ($T_c=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameters	Min	Typ	Max	Units	Conditions
Static Characteristics						
B_{VDSS}	Drain-Source Breakdown VoltageCurrent (Note 1)	800	--	--	mA	$I_D=250\mu\text{A}$ $V_{GS}=0\text{V}$, $T_J=25^\circ\text{C}$
$V_{GS(\text{th})}$	Gate Threshold Voltage	3.0	--	5.0	V	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$
$R_{DS(\text{on})}$	Drain-Source On-Resistance	--	0.68	1.0	Ω	$V_{GS}=10\text{V}$, $I_D=5\text{A}$
I_{GSS}	Gate-Body Leakage Current	--	--	± 100	nA	$V_{GS}=\pm 30\text{V}$, $V_{DS}=0$
I_{DSS}	Zero Gate Voltage Drain Current	--	--	1	μA	$V_{DS}=800\text{V}$, $V_{GS}=0$
Switching Characteristics						
$T_{d(\text{on})}$	Turn-On Delay Time	--	50	110	ns	$V_{DS}=400\text{V}$, $I_D=10\text{A}$, $R_G=25\Omega$ (Note 2)
T_r	Rise Time	--	130	270	ns	
$T_{d(\text{off})}$	Turn-Off Delay Time	--	90	190	ns	
T_f	Fall Time	--	80	165	ns	
Q_g	Total Gate Charge	--	45	58	nC	$V_{DS}=640\text{V}$, $V_{GS}=10\text{V}$, $I_D=10\text{A}$ (Note 2)
Q_{gs}	Gate-Source Charge	--	13.5	--	nC	
Q_{gd}	Gate-Drain Charge	--	17	--	nC	
Dynamic Characteristics						
C_{iss}	Input Capacitance	--	2150	2800	pF	$V_{DS}=25\text{V}$, $V_{GS}=0$, $f=1\text{MHz}$
C_{oss}	Output Capacitance	--	180	230	pF	
C_{rss}	Reverse Transfer Capacitance	--	15	20	pF	
I_s	Continuous Drain-Source Diode Forward Current (Note 2)	--	--	10	A	
V_{SD}	Diode Forward On-Voltage	--	--	1.4	V	$I_s=10\text{A}$, $V_{GS}=0$
$R_{th(j-c)}$	Thermal Resistance, Junction to Case	--	--	2.6	$^\circ\text{C}/\text{W}$	

Note 1: Repetitive Rating : Pulse width limited by maximum junction temperature

Note 2: Pulse test: PW <= 300us , duty cycle <= 2%.

Ratings and Characteristic curves

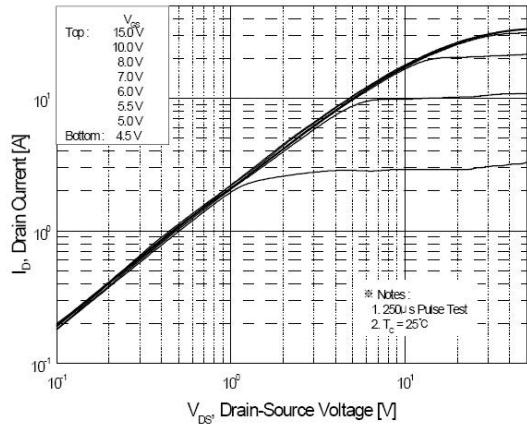


Figure 1. On-Region Characteristics

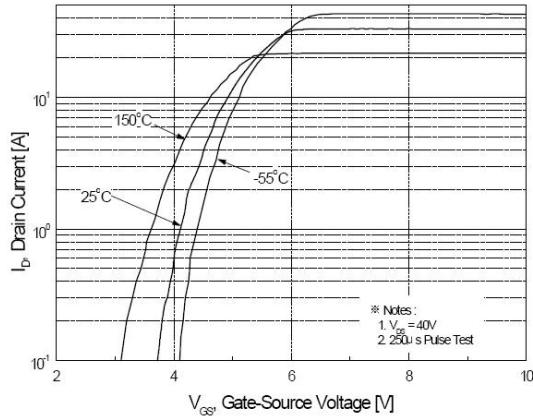


Figure 2. Transfer Characteristics

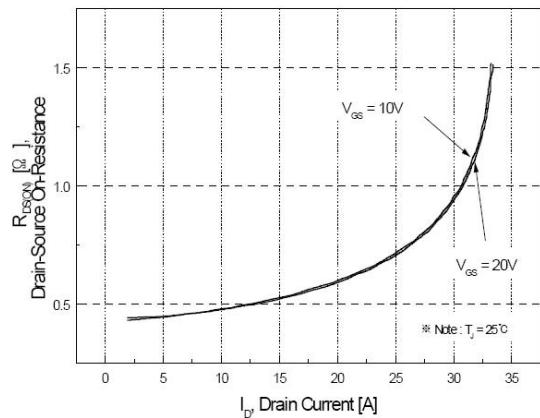


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

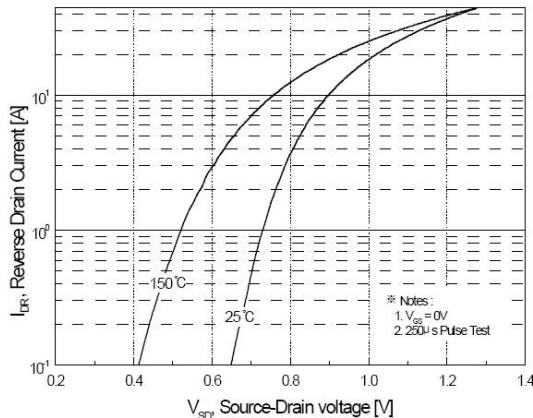


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

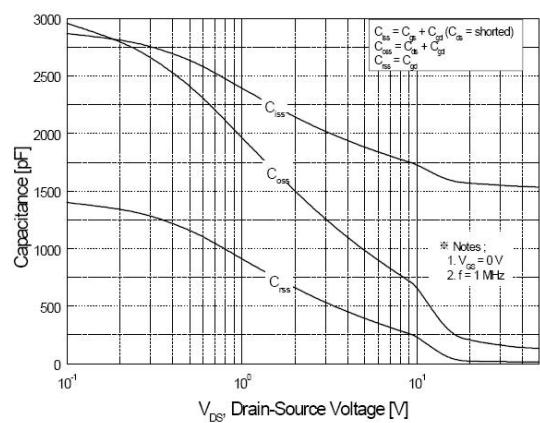


Figure 5. Capacitance Characteristics

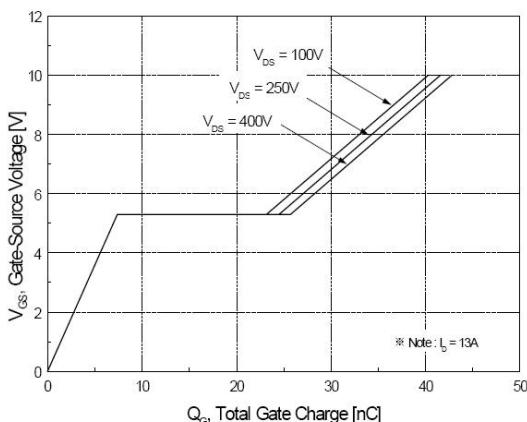
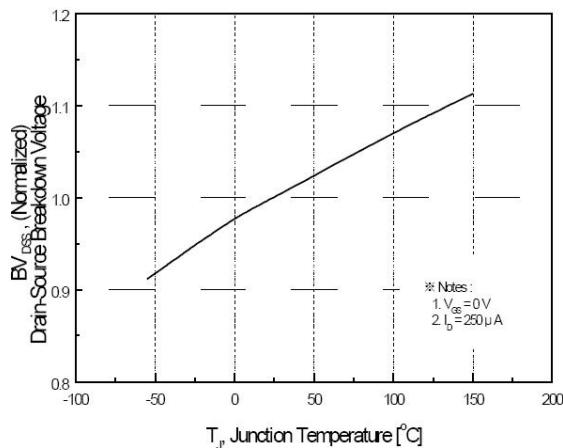
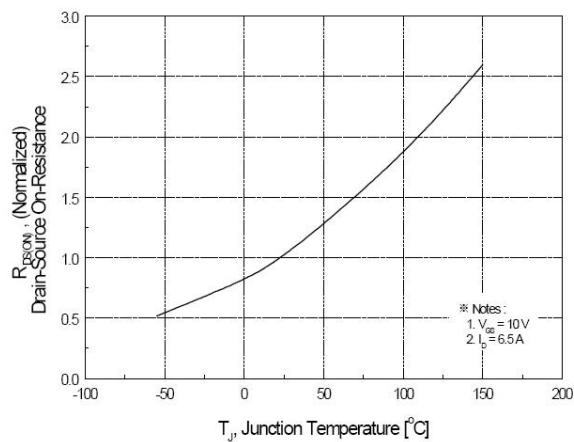


Figure 6. Gate Charge Characteristics



**Figure 7. Breakdown Voltage Variation
vs Temperature**



**Figure 8. On-Resistance Variation
vs Temperature**

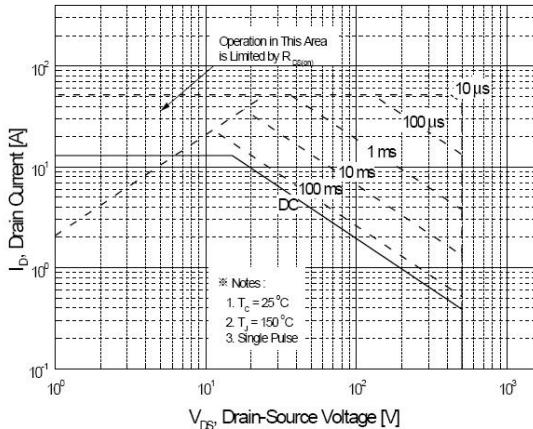
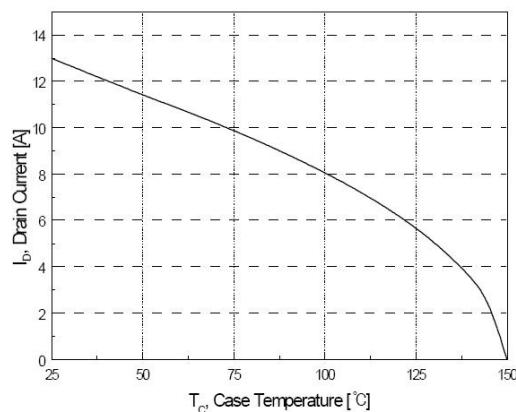


Figure 9. Maximum Safe Operating Area



**Figure 10. Maximum Drain Current
vs Case Temperature**

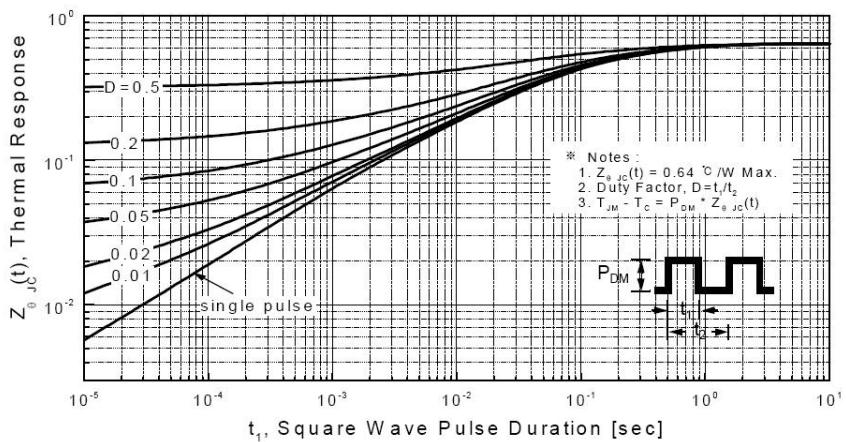


Figure 11. Transient Thermal Response Curve

Fig 12. Gate Charge Test Circuit & Waveform

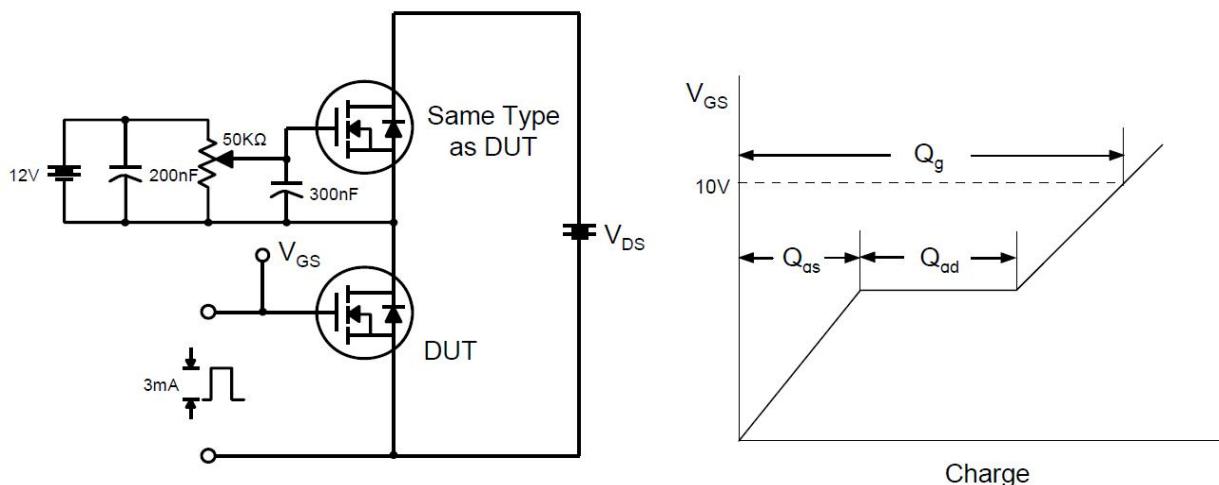


Fig 13. Resistive Switching Test Circuit & Waveforms

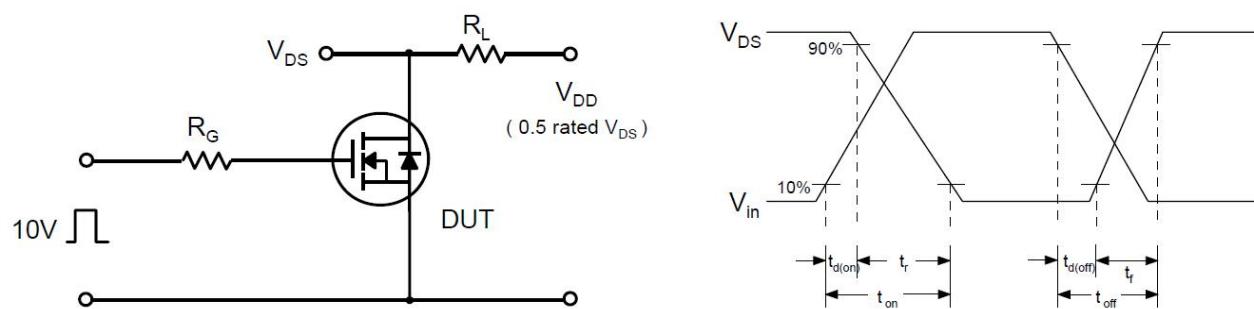


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

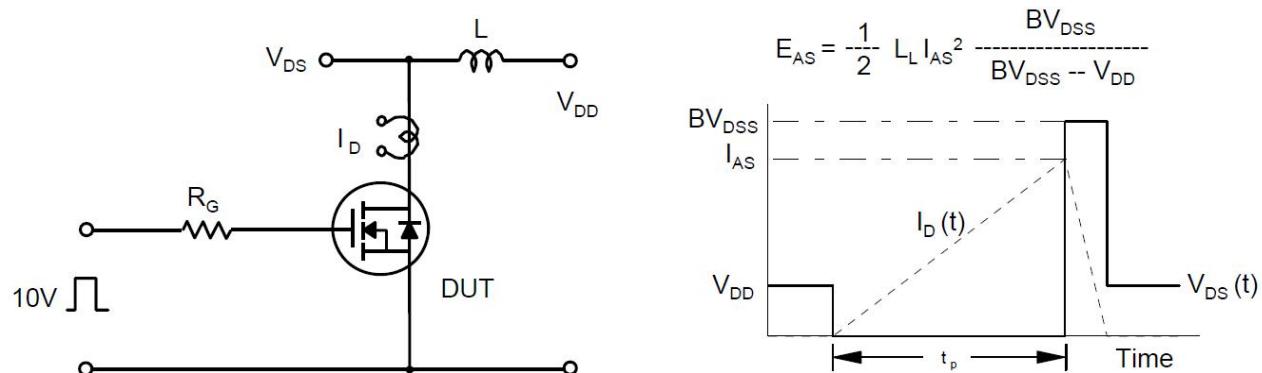
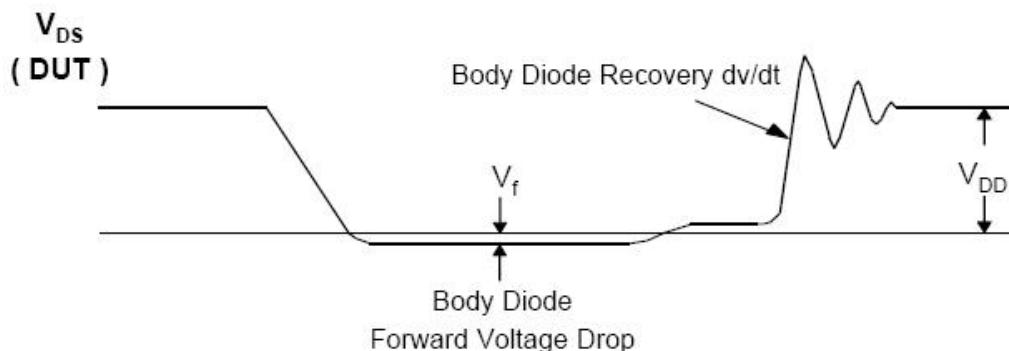
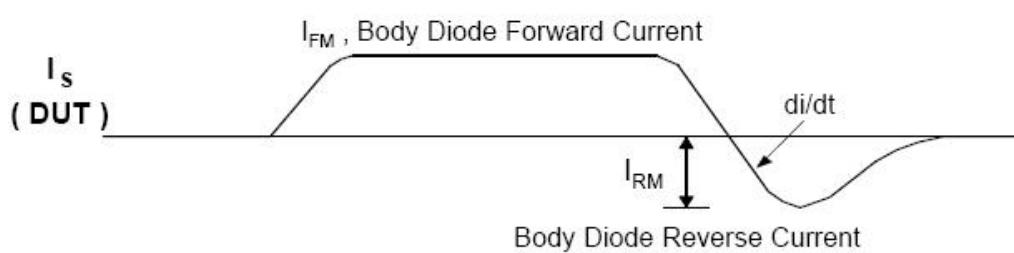
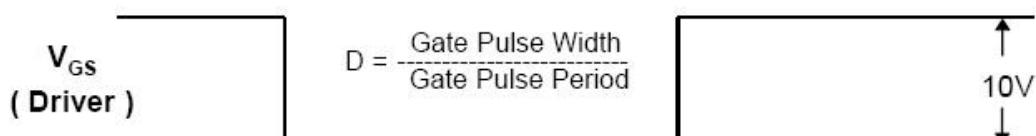
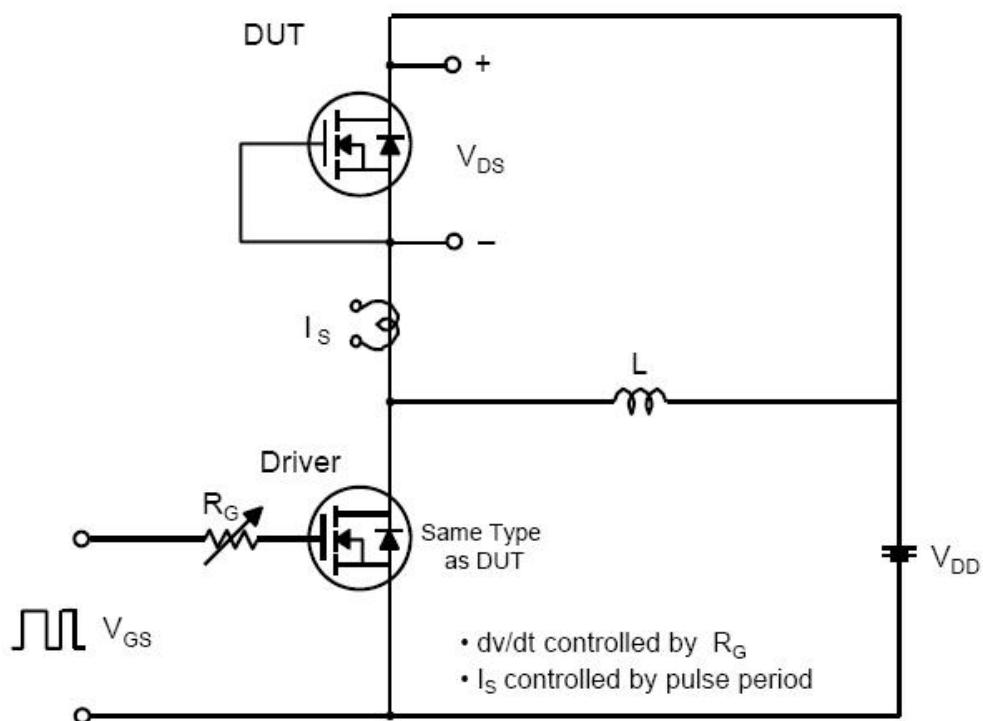
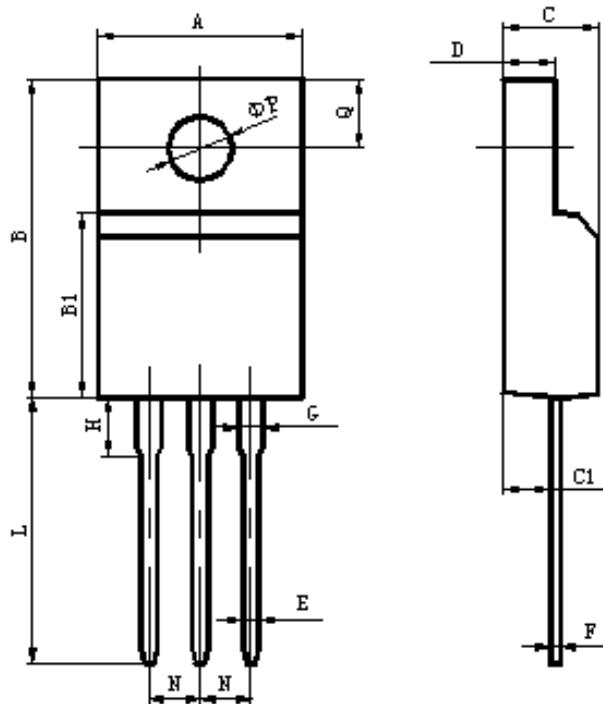


Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Mechanical Data-TO-220F Single



Items	Values(mm)	
	MIN	MAX
A	9.60	10.4
B	15.4	16.2
B1	8.90	9.50
C	4.30	4.90
C1	2.10	3.00
D	2.40	3.00
E	0.60	1.00
F	0.30	0.60
G	1.12	1.42
H	3.40	3.80
	2.40	2.90
L*	12.0	14.0
N	2.34	2.74
Q	3.15	3.55
ΦP	2.90	3.30